UNISONIC TECHNOLOGIES CO., LTD

3N65K-MK4

Preliminary

Power MOSFET

3A, 650V N-CHANNEL POWER MOSFET

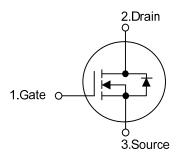
■ DESCRIPTION

The UTC **3N65K-MK4** is a high voltage and high current power MOSFET designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and high rugged avalanche characteristics. This power MOSFET is usually used in high speed switching applications at power supplies, PWM motor controls, high efficient DC to DC converters and bridge circuits.

■ FEATURES

- * $R_{DS(ON)}$ < 3.5 Ω @ V_{GS} = 10V, I_{D} = 1.5A
- * Fast switching capability
- * Avalanche energy specified
- * Improved dv/dt capability, high ruggedness

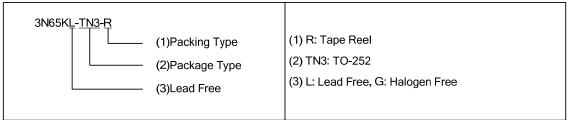




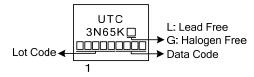
ORDERING INFORMATION

0	Dookogo	Pin Assignment			Dooking		
Lead Free	Halogen Free	Package	1	2	3	Packing	
3N65KL-TN3-F	3N65KG-TN3-R	TO-252	G	D	S	Tape Reel	

Note: Pin Assignment: G: Gate D: Drain S: Source



MARKING



1 TO-252

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■ ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V_{DSS}	650	V	
Gate-Source Voltage		V_{GSS}	±30	V	
Avalanche Current (Note 2)		I _{AR}	3.0	Α	
Continuous Drain Current		I _D	3.0	Α	
Pulsed Drain Current (Note 2)		I_{DM}	12	Α	
Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	130	mJ	
	Repetitive (Note 2)	E _{AR}	7.5	mJ	
Peak Diode Recovery dv/dt (Note 4)		dv/dt	4.5	V/ns	
Power Dissipation		Б	50	W	
Derate above 25°C		P _D	0.4	W/°C	
Junction Temperature		T_J	+150	°C	
Operating Temperature		T_{OPR}	-55 ~ + 150	°C	
Storage Temperature		T _{STG}	-55 ~ +150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by T_J.
- 3. L=28mH, I_{AS} =3A, V_{DD} =50V, R_{G} =25 Ω , Starting T_{J} = 25°C
- 4. $I_{SD} \le 3.0$ A, di/dt ≤ 200 A/ μ s, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25$ °C

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	θ_{JA}	110	°C/W	
Junction to Case	θ_{JC}	2.5	°C/W	

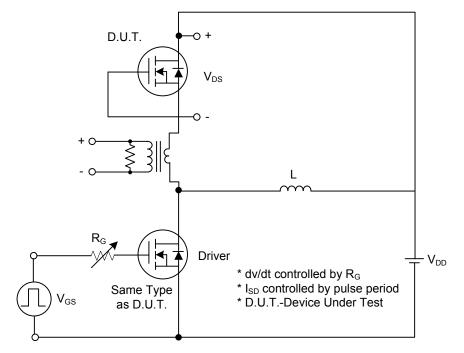
■ **ELECTRICAL CHARACTERISTICS** (T_C =25°C, unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV _{DSS}	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	650			V
Drain-Source Leakage Current		I _{DSS}	V _{DS} = 650 V, V _{GS} = 0 V			10	μA
Cata Causa Laglana Cumant	Forward	1000	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
Gate-Source Leakage Current	Reverse		$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
Breakdown Voltage Temperature Coefficient		$\triangle BV_{DSS}/\triangle T_J$	I _D =250μA,Referenced to 25°C		0.6		V/°C
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.5		4.5	V
Static Drain-Source On-State Resistance		R _{DS(ON)}	$V_{GS} = 10V, I_D = 1.5A$			3.5	Ω
DYNAMIC CHARACTERISTICS							
Input Capacitance		C _{ISS}	05)()(385		pF
Output Capacitance		Coss	V _{DS} = 25V, V _{GS} = 0V, If = 1MHz		60		pF
Reverse Transfer Capacitance		C_{RSS}			5		pF
SWITCHING CHARACTERISTICS	3						
Turn-On Delay Time		$t_{D(ON)}$			43		ns
Turn-On Rise Time		t_R	$V_{DD} = 30V, I_D = 0.5A,$		20		ns
Turn-Off Delay Time		$t_{D(OFF)}$	$R_G = 25\Omega \text{ (Note 1, 2)}$		90		ns
Turn-Off Fall Time		t_{F}			18		ns
Total Gate Charge		Q_G	V - 50VI - 4.2A		14		nC
Gate-Source Charge		Q_GS	V _{DS} = 50V,I _D = 1.3A, V _{GS} = 10 V (Note 1, 2)		5.8		nC
Gate-Drain Charge		Q_{DD}	V _{GS} - 10 V (Note 1, 2)		1.7		nC
SOURCE- DRAIN DIODE RATING	S AND CH	HARACTERIST	rics	-	-		
Drain-Source Diode Forward Voltage		V_{SD}	$V_{GS} = 0 \text{ V}, I_{S} = 3.0 \text{ A}$			1.4	V
Maximum Continuous Drain-Source Diode		I-				3.0	Α
Forward Current		I _S				3.0	^
Maximum Pulsed Drain-Source Diode		I _{SM}				12	Α
Forward Current						12	^

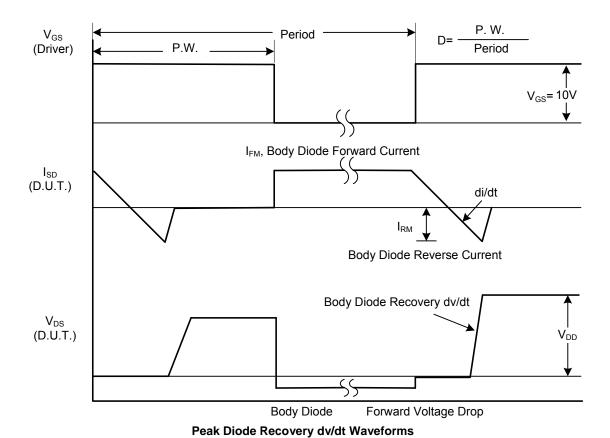
Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle≤2%

^{2.} Essentially independent of operating temperature

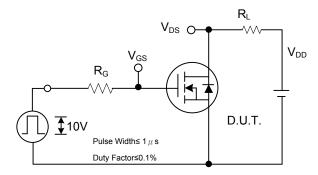
TEST CIRCUITS AND WAVEFORMS



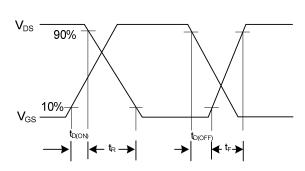
Peak Diode Recovery dv/dt Test Circuit



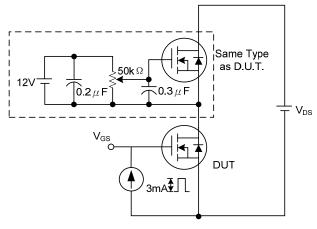
■ TEST CIRCUITS AND WAVEFORMS (Cont.)



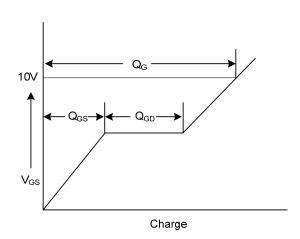
Switching Test Circuit



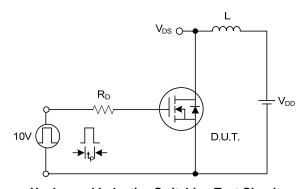
Switching Waveforms



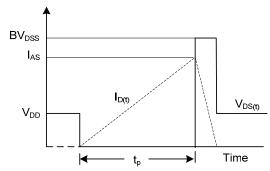
Gate Charge Test Circuit



Gate Charge Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

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